Table 1. Reliability test results

| Test Items<br>試験項目                       | Test conditions<br>試験条件  | Number of samples<br>試料数 | Number of failures<br>故障数 |  |
|--|--|--------------------------|---------------------------|--|
| Resistance to soldering heat<br>はんだ耐熱性   | Solder temperature : 260°C Time : 10seconds                                  | 5                        | 0                         |  |
| Solderability<br>はんだ付け性                  | Solder temperature : 250°C Time : 10seconds                                  | 5                        | 0                         |  |
| Temperature cycle<br>温度サイクル              | -40℃~125℃<br>30minutes each<br>100cycles                                     | 5                        | 0                         |  |
| Terminal strength(pull)<br>端子強度(引張り)     | Control terminal : Weight 5N<br>Power terminal : Weight 10N<br>10seconds     | 5                        | 0                         |  |
| Terminal strength(Bending)<br>端子強度(曲げ)   | Control terminal: Weight 2.5N Power terminal: Weight 5N 90deg. Bend 2times   | 5                        | 0                         |  |
| Mounting torque<br>締付けトルク                | Mounting screw : M3 0.78N·m  | 5                        | 0                         |  |
| High temperature storage<br>高温保存         | $T_a$ =125 $^{\circ}$ C<br>1000hours   | 5                        | 0                         |  |
| Temperature humidity storage<br>高温高湿保存   | T <sub>a</sub> =60℃<br>RH=90%<br>1000hours                                   | 5                        | 0                         |  |
| High-Temperature Reverse-Bias<br>高温逆バイアス | T <sub>ch</sub> =125℃<br>V <sub>DS</sub> =0.85*V <sub>DSS</sub><br>1000hours | 5                        | 0                         |  |
| Intermittent operating life<br>断続動作      | △T <sub>j</sub> =100°C<br>5000cycles   | 5                        | 0                         |  |

Table 2. Failure criteria

| Parameter            | Measurement conditions<br>測定条件   | Criteria for failure<br>故障判定基準 |                   | Remarks<br>備考 |
|----------------------|--|--------------------------------|-------------------|---------------|
| 測定項目                 |  | Lower Limit<br>下限              | Upper Limit<br>上限 |               |
| I <sub>DSS</sub>     | V <sub>DS</sub> =Rated voltage   | _                              | U.S.L.×2.0        |               |
| V <sub>SD(off)</sub> | -I <sub>D</sub> =Rated current   | _                              | U.S.L.×1.2        |               |
| $V_{DS(on)}$         | I <sub>D</sub> =Rated current, V <sub>D</sub> =V <sub>DB</sub> =18V, V <sub>IN</sub> =5V |                                | U.S.L.×1.2        |               |
| VF                   | I <sub>F</sub> =10mA including voltage drop by limiting resistor                         |                                | U.S.L.×1.2        |               |
| I <sub>D</sub>       | $V_D=18V$ , $V_{IN}=0V$  |                                | U.S.L.×2.0        |               |
| I <sub>DB</sub>      | $V_D=V_{DB}=18V$ , $V_{IN}=0V$   |                                | U.S.L.×2.0        |               |
| Dielectric withstand | 1500Vrms, Sinusoidal, AC 1 minute, all connection pins to heat-sink plate                | Break down                     |                   | _             |

Note: The reliability tests are performed the representative products for the product group.

The measurement items of each test are selected according to our standards.

The symbols in the table are as follows. U.S.L.: Upper Specification Limit

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